

IEC TR 63396

Edition 1.0 2021-11

TECHNICAL REPORT







THIS PUBLICATION IS COPYRIGHT PROTECTED Copyright © 2021 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Central Office 3, rue de Varembé CH-1211 Geneva 20 Switzerland

Tel.: +41 22 919 02 11 info@iec.ch www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search - webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee, ...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore iec ch/csc If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch. IEC TR 63396:2021

IEC online collection - oc.iec.ch

Discover our powerful search engine and read freely all the publications previews. With a subscription you will always have access to up to date content tailored to your needs.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 000 terminological entries in English and French, with equivalent terms in 18 additional languages. Also known as the International Electrotechnical Vocabulary



https://standards.iteh.ai/catalog/standards/sist/533b1348-7f51-4cce-b0a5

6ffe84cedab7/iec-tr-63396-2021



IEC TR 63396

Edition 1.0 2021-11

TECHNICAL REPORT

Noise measurement method on power capacitorsEVIEW (standards.iteh.ai)

IEC TR 63396:2021 https://standards.iteh.ai/catalog/standards/sist/533b1348-7f51-4cce-b0a5-6ffe84cedab7/iec-tr-63396-2021

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ICS 29.120.99; 31.060.70

ISBN 978-2-8322-1049-8

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD	.4
INTRODUCTION	.6
1 Scope	.7
2 Normative references	.7
3 Terms and definitions	.7
4 Noise measurement	10
4.1 Power injection conditions for capacitors	
4.1.1 Current injection conditions for shunt capacitor units	
4.1.2 Current injection conditions for AC filter capacitor units	
4.1.3 Current and voltage injection conditions for DC filter capacitor units	
4.2 Measuring environment	
4.3 Characteristics for basic acoustic instruments	11
4.4 Arrangement of the power capacitors	11
4.5 Arrangement of the microphone	12
4.6 Measurement on sound pressure levels	12
4.6.1 General	
4.6.2 Calculation of average sound pressure level at measurement surface	
5 Measurement of uncertainty TANDARD PREVIEW	14
6 Test report Annex A (informative) Microphone arrangement on hoise measurement surface of	15
Annex A (informative) Microphone arrangement on noise measurement surface of	
power capacitors	
A.1 Measurement surface <u>IEC TR 63396:2021</u>	16
A.2 Measurement positions and orientation of microphone	17
Annex B (informative) Typical test circuit for power capacitor noise measurement	
B.1 Shunt and AC filter power capacitor noise test circuit	
B.2 DC filter power capacitor noise test circuit	
Annex C (informative) Typical format of power capacitor noise test report	
C.1 Basic information in the typical test report	
C.2 Sound level meter parameters	
C.3 Test parameter configuration	
C.4 Noise measurement data	
C.5 Meteorological conditions of the test environment	
C.6 Measuring personnel and time	
Bibliography	22
	40
Figure A.1 – Schematic diagram of installation of the test object	
Figure A.2 – Microphone positions on the parallelepiped measurement surface	17
Figure B.1 – Schematic diagram of shunt and AC filter power capacitor noise test circuit	18
Figure B.2 – Schematic diagram of DC filter power capacitor noise test circuit	

13
17
20
20
20
-

iTeh STANDARD PREVIEW (standards.iteh.ai)

INTERNATIONAL ELECTROTECHNICAL COMMISSION

NOISE MEASUREMENT METHOD ON POWER CAPACITORS

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject deall with may participate in this preparatory work. International, governmental and non-governmental organizations for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

IEC 63396 has been prepared by technical committee 33: Power capacitors and their applications. It is a Technical Report.

The text of this Technical Report is based on the following documents:

Draft	Report on voting
33/658/DTR	33/663/RVDTR

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Report is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

- 5 -

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

iTeh STANDARD PREVIEW (standards.iteh.ai)

INTRODUCTION

Power capacitors are important equipment for HVDC project, but at the same time they are also the main noise source. However, there is no IEC document which is specific to the noise measurement on power capacitors until now.

In recent years, Chinese authoritative testing organizations have conducted a large number of experiments in this area. Now, many laboratories in China are able to simulate the actual operating conditions of power capacitors in HVDC converter stations for noise testing.

This new technical report is aimed to document a feasible method to measure power capacitor's noise in AC and DC systems, in particular in HVDC converter stations, based on the experience developed in China. Furthermore, the testing laboratories could also check and validate periodically the common technical parameters of the noise measurement on power capacitors in an uniform way by this method, in order to promote the practical application of the measurement method and possibly to improve it (in view of a possible future conversion of the technical report to a technical specification).

This document is intended to fill the gap in this technical field, and to promote the construction of environmentally friendly AC and DC substations.

iTeh STANDARD PREVIEW (standards.iteh.ai)

NOISE MEASUREMENT METHOD ON POWER CAPACITORS

1 Scope

The object of this Technical Report is to document a method for the sound pressure level measurement on power capacitor units, by which the sound power level of power capacitor units is determined.

This method is applicable to shunt capacitor units and AC filter capacitor units for AC power systems with a nominal voltage of 1 kV and above and a frequency of 50 Hz or 60 Hz.

This method also applies to the DC filter capacitor units.

Other measurements on power capacitor units can be implemented with reference to this method.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61260-1:2014, *Electroacoustics* – <u>Qctave(band)and</u> fractional-octave-band filters – Part 1: Specifications https://standards.iteh.ai/catalog/standards/sist/533b1348-7f51-4cce-b0a5-6ffe84cedab7/iec-tr-63396-2021

IEC 61672-1:2013, Electroacoustics – Sound level meters – Part 1: Specifications

ISO 3744:2010, Acoustics – Determination of sound power levels and sound energy levels of noise sources using sound pressure – Engineering methods for an essentially free field over a reflecting plane

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.1 noise unwanted sound

[SOURCE: IEC TS 61973:2012, 3.1.13]

3.2 sound pressure

fluctuating pressure superimposed on the static pressure

Note 1 to entry: Sound pressure is expressed in pascals (Pa).

Note 2 to entry: Sound pressure is usually expressed through the use of a decibel scale, as sound pressure level.

- 8 -

[SOURCE: IEC TS 61973:2012, 3.1.3]

3.3 sound pressure level

 L_p

logarithm of the ratio of the RMS value of a given sound pressure to the reference sound pressure

$$L_p = 10 \log \frac{p^2}{p_0^2} = 20 \log \frac{p}{p_0} , \qquad (1)$$

where:

- *p* is the measured RMS sound pressure, in pascals;
- p_0 is the reference RMS pressure of 2 × 10⁻⁵ Pa, which corresponds to the 0 dB as threshold of audibility.

Note 1 to entry: log(x) means the logarithm with base 10 of x; this convention is used throughout this document.

Note 2 to entry: The sound pressure level (L_p) is expressed in decibels (dB).

Note 3 to entry: Sound pressure level is measured with sound level meters, which normally incorporate a frequencyweighting filter. For further details see 3.2.3 of IEC TS 61973:2012.

Note 4 to entry: Since the sound level distribution measured around sound emitting objects is usually non-uniform it is normally necessary to assess sound levels on spatial average figures gained from several measuring positions rather than on one single discrete position.

[SOURCE: IEC TS 61973:2012, 3.1.4]

3.4

sound power

Р

through a surface, product of the sound pressure, p, and the component of the particle velocity, u_n , at a point on the surface in the direction normal to the surface, integrated over that surface

Note 1 to entry: Sound power is expressed in watts.

Note 2 to entry: The quantity relates to the rate per time at which airborne sound energy is radiated by a source.

[SOURCE: ISO 3744:2010, 3.20]

3.5

sound power level

 L_w

ten times the logarithm to the base 10 of the ratio of the sound power of a source, P, to a reference value, P_0 , expressed in decibels (dB)

$$L_W = 10\log\frac{P}{P_0} \tag{2}$$

where the reference value, P_0 , is 1 pW

Note 1 to entry: If a specific weighting as specified in IEC 61672-1 and/or specific frequency bands are applied, this is indicated by appropriate subscripts; e.g. $L_{W(A)}$ denotes the A-weighted sound power level.

[SOURCE: ISO 3744:2010, 3.21]

3.6

reference box

hypothetical right parallelepiped terminating on the reflecting plane(s) on which the noise source under test is located, that just encloses the source including all the significant sound radiating components and any test table on which the source is mounted

Note 1 to entry: The test table as small as possible be used.

Note 2 to entry: Reference radiating plane of capacitor unit is the cuboid surface consisting of the six sides of the capacitor unit enclosure only and excluding the wiring terminals.

[SOURCE: ISO 3744:2010, 3.10]

3.7 measurement surface

S

hypothetical surface of an area, S, on which the microphone positions are located at which the sound pressure levels are measured, enveloping the noise source under test and terminating on the reflecting plane(s) on which the source is located

[SOURCE: ISO 3744:2010; 3.14] TANDARD PREVIEW

3.8

(standards.iteh.ai)

background noise

noise from all sources other than the noise source under test

https://standards.iteh.ai/catalog/standards/sist/533b1348-7f51-4cce-b0a5-

Note 1 to entry: Background noise includes contributions from airborne sound, noise from structure-borne vibration, and electrical noise in the instrumentation.

Note 2 to entry: The background noise considers noise from the associated power equipment which operates and stops simultaneously with the capacitor unit.

[SOURCE: ISO 3744:2010, 3.15]

3.9

synthesis of sound pressure level

superposition of sound pressure levels generated by two or more sound sources at a certain point in the sound field

3.10

directivity index

 D_{Ii}

measure of the extent to which a noise source under test radiates sound in the direction of the i_{th} microphone position on a measurement surface, relative to the mean sound radiation over the measurement surface

$$D_{Ii}^{*} = L_{pi(ST)} - (\overline{L_{p(ST)}} - K_{1})$$
(3)

where

 $L_{pi(ST)}$ is the background noise-corrected time-averaged (or single event time-integrated) sound pressure level for the i_{th} microphone position on the measurement surface, with the noise source under test (ST) in operation, in decibels;